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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	2400
Number of Logic Elements/Cells	10800
Total RAM Bits	81920
Number of I/O	166
Number of Gates	468252
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	240-BFQFP Exposed Pad
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv400-6hq240c

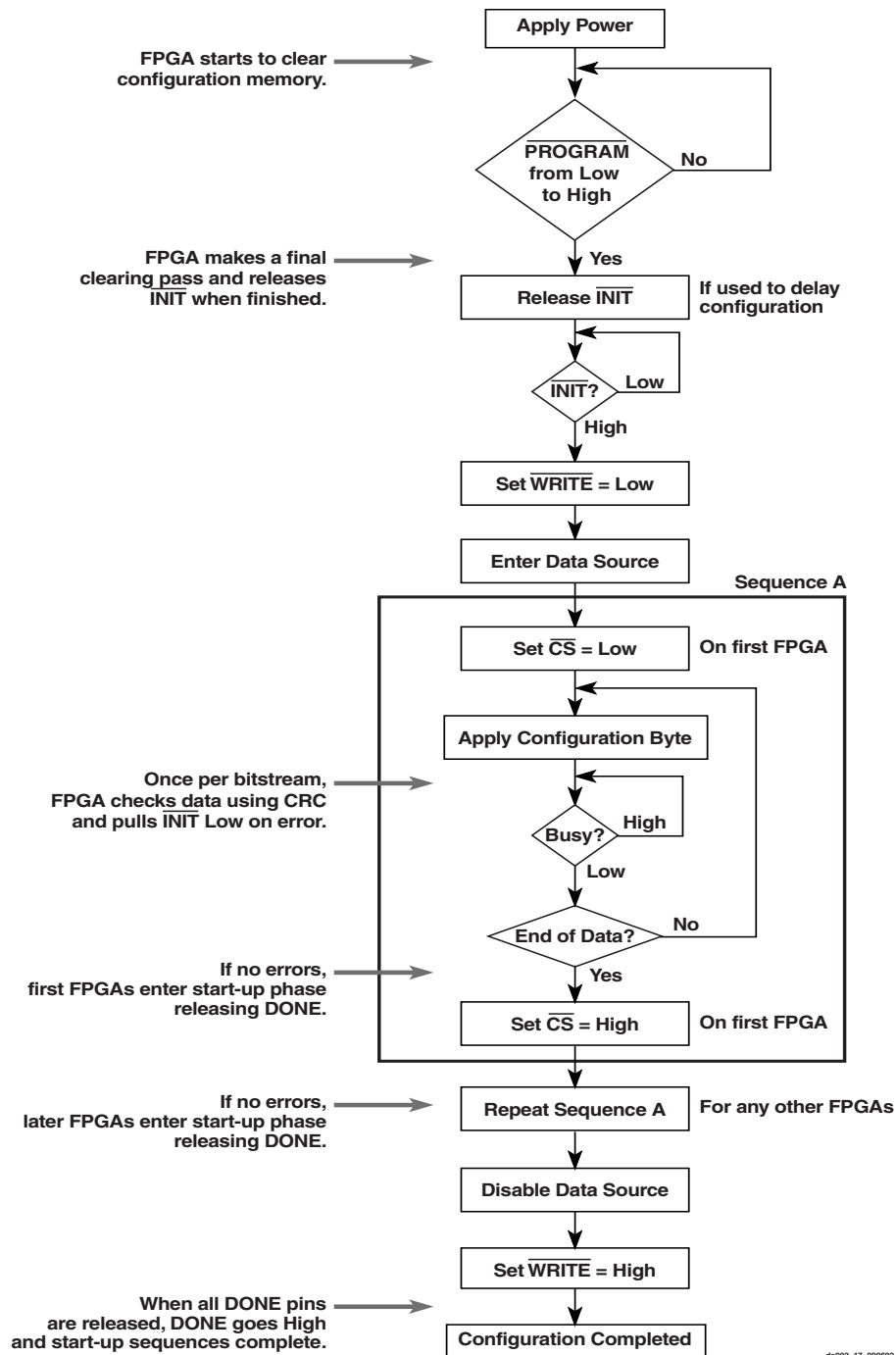


Figure 17: SelectMAP Flowchart for Write Operation

Abort

During a given assertion of \overline{CS} , the user cannot switch from a write to a read, or vice-versa. This action causes the current packet command to be aborted. The device will remain BUSY until the aborted operation has completed. Following an abort, data is assumed to be unaligned to word boundar-

ies, and the FPGA requires a new synchronization word prior to accepting any new packets.

To initiate an abort during a write operation, de-assert \overline{WRITE} . At the rising edge of CCLK, an abort is initiated, as shown in Figure 18.

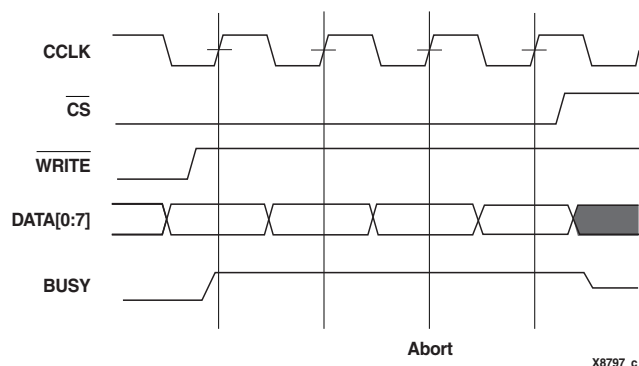


Figure 18: SelectMAP Write Abort Waveforms

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the **PROGRAM** pin must be pulled High prior to reconfiguration. A Low on the **PROGRAM** pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the **CFG_IN** instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the **CFG_IN** instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the **JSTART** instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting **PROGRAM**.

The end of the memory-clearing phase is signalled by **INIT** going High, and the completion of the entire process is signalled by **DONE** going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

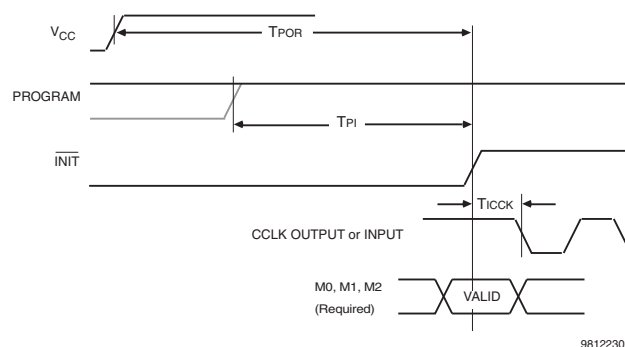


Figure 19: Power-Up Timing Configuration Signals

Table 10: Power-up Timing Characteristics

Description	Symbol	Value	Units
Power-on Reset	T _{POR}	2.0	ms, max
Program Latency	T _{PL}	100.0	μs, max
CCLK (output) Delay	T _{ICCK}	0.5	μs, min
		4.0	μs, max
Program Pulse Width	T _{PROGRAM}	300	ns, min

Delaying Configuration

INIT can be held Low using an open-drain driver. An open-drain is required since **INIT** is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after **DONE** goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the **DONE** pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Data Stream Format

Virtex devices are configured by sequentially loading frames of data. **Table 11** lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 “Virtex Configuration Architecture Advanced Users Guide”.

Table 11: Virtex Bit-Stream Lengths

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, “0” hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036, 111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.

Virtex DC Characteristics

Absolute Maximum Ratings

Symbol	Description ⁽¹⁾			Units
V_{CCINT}	Supply voltage relative to GND ⁽²⁾		–0.5 to 3.0	V
V_{CCO}	Supply voltage relative to GND ⁽²⁾		–0.5 to 4.0	V
V_{REF}	Input Reference Voltage		–0.5 to 3.6	V
V_{IN}	Input voltage relative to GND ⁽³⁾	Using V_{REF}	–0.5 to 3.6	V
		Internal threshold	–0.5 to 5.5	V
V_{TS}	Voltage applied to 3-state output		–0.5 to 5.5	V
V_{CC}	Longest Supply Voltage Rise Time from 1V-2.375V		50	ms
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature ⁽⁴⁾	Plastic Packages	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings can cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time can affect device reliability.
- Power supplies can turn on in any order.
- For protracted periods (e.g., longer than a day), V_{IN} should not exceed V_{CCO} by more than 3.6 V.
- For soldering guidelines and thermal considerations, see the "Device Packaging" information on www.xilinx.com.

Recommended Operating Conditions

Symbol	Description		Min	Max	Units
$V_{CCINT}^{(1)}$	Input Supply voltage relative to GND, $T_J = 0\text{ °C to }+85\text{ °C}$	Commercial	2.5 – 5%	2.5 + 5%	V
	Input Supply voltage relative to GND, $T_J = -40\text{ °C to }+100\text{ °C}$	Industrial	2.5 – 5%	2.5 + 5%	V
$V_{CCO}^{(4)}$	Supply voltage relative to GND, $T_J = 0\text{ °C to }+85\text{ °C}$	Commercial	1.4	3.6	V
	Supply voltage relative to GND, $T_J = -40\text{ °C to }+100\text{ °C}$	Industrial	1.4	3.6	V
T_{IN}	Input signal transition time			250	ns

Notes:

- Correct operation is guaranteed with a minimum V_{CCINT} of 2.375 V (Nominal V_{CCINT} –5%). Below the minimum value, all delay parameters increase by 3% for each 50-mV reduction in V_{CCINT} below the specified range.
- At junction temperatures above those listed as Operating Conditions, delay parameters do increase. Please refer to the TRCE report.
- Input and output measurement threshold is ~50% of V_{CC} .
- Min and Max values for V_{CCO} are I/O Standard dependant.

DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Device	Min	Max	Units
V_{DRINT}	Data Retention V_{CCINT} Voltage (below which configuration data can be lost)	All	2.0		V
V_{DRIO}	Data Retention V_{CCO} Voltage (below which configuration data can be lost)	All	1.2		V
I_{CCINTQ}	Quiescent V_{CCINT} supply current ^(1,3)	XCV50		50	mA
		XCV100		50	mA
		XCV150		50	mA
		XCV200		75	mA
		XCV300		75	mA
		XCV400		75	mA
		XCV600		100	mA
		XCV800		100	mA
		XCV1000		100	mA
I_{CCOQ}	Quiescent V_{CCO} supply current ⁽¹⁾	XCV50		2	mA
		XCV100		2	mA
		XCV150		2	mA
		XCV200		2	mA
		XCV300		2	mA
		XCV400		2	mA
		XCV600		2	mA
		XCV800		2	mA
		XCV1000		2	mA
I_{REF}	V_{REF} current per V_{REF} pin	All		20	μ A
I_L	Input or output leakage current	All	-10	+10	μ A
C_{IN}	Input capacitance (sample tested)	BGA, PQ, HQ, packages		8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{in} = 0$ V, $V_{CCO} = 3.3$ V (sample tested)	All	Note (2)	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ $V_{in} = 3.6$ V (sample tested)		Note (2)	0.15	mA

Notes:

1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.
3. Multiply I_{CCINTQ} limit by two for industrial grade.

Description	Device	Symbol	Speed Grade				Units
			Min	-6	-5	-4	
Setup and Hold Times with respect to Clock CLK at IOB input register ⁽¹⁾			Setup Time / Hold Time				
Pad, no delay	All	T _{IOPICK} /T _{IOICKP}	0.8 / 0	1.6 / 0	1.8 / 0	2.0 / 0	ns, min
Pad, with delay	XCV50	T _{IOPICKD} /T _{IOICKPD}	1.9 / 0	3.7 / 0	4.1 / 0	4.7 / 0	ns, min
	XCV100		1.9 / 0	3.7 / 0	4.1 / 0	4.7 / 0	ns, min
	XCV150		1.9 / 0	3.8 / 0	4.3 / 0	4.9 / 0	ns, min
	XCV200		2.0 / 0	3.9 / 0	4.4 / 0	5.0 / 0	ns, min
	XCV300		2.0 / 0	3.9 / 0	4.4 / 0	5.0 / 0	ns, min
	XCV400		2.1 / 0	4.1 / 0	4.6 / 0	5.3 / 0	ns, min
	XCV600		2.1 / 0	4.2 / 0	4.7 / 0	5.4 / 0	ns, min
	XCV800		2.2 / 0	4.4 / 0	4.9 / 0	5.6 / 0	ns, min
	XCV1000		2.3 / 0	4.5 / 0	5.0 / 0	5.8 / 0	ns, min
ICE input	All	T _{IOICECK} /T _{IOCKICE}	0.37/ 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, max
Set/Reset Delays							
SR input (IFF, synchronous)	All	T _{IOSRCKI}	0.49	1.0	1.1	1.3	ns, max
SR input to IQ (asynchronous)	All	T _{IOSRIQ}	0.70	1.4	1.6	1.8	ns, max
GSR to output IQ	All	T _{GSRQ}	4.9	9.7	10.9	12.5	ns, max

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.
2. Input timing for LVTTTL is measured at 1.4 V. For other I/O standards, see [Table 3](#).

IOB Output Switching Characteristics Standard Adjustments

Output delays terminating at a pad are specified for LVTTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays by the values shown.

Description	Symbol	Standard ⁽¹⁾	Speed Grade				Unit s
			Min	-6	-5	-4	
Output Delay Adjustments							
Standard-specific adjustments for output delays terminating at pads (based on standard capacitive load, Csl)	T _{OLVTTL_S2}	LVTTL, Slow, 2 mA	4.2	14.7	15.8	17.0	ns
	T _{OLVTTL_S4}	4 mA	2.5	7.5	8.0	8.6	ns
	T _{OLVTTL_S6}	6 mA	1.8	4.8	5.1	5.6	ns
	T _{OLVTTL_S8}	8 mA	1.2	3.0	3.3	3.5	ns
	T _{OLVTTL_S12}	12 mA	1.0	1.9	2.1	2.2	ns
	T _{OLVTTL_S16}	16 mA	0.9	1.7	1.9	2.0	ns
	T _{OLVTTL_S24}	24 mA	0.8	1.3	1.4	1.6	ns
	T _{OLVTTL_F2}	LVTTL, Fast, 2mA	1.9	13.1	14.0	15.1	ns
	T _{OLVTTL_F4}	4 mA	0.7	5.3	5.7	6.1	ns
	T _{OLVTTL_F6}	6 mA	0.2	3.1	3.3	3.6	ns
	T _{OLVTTL_F8}	8 mA	0.1	1.0	1.1	1.2	ns
	T _{OLVTTL_F12}	12 mA	0	0	0	0	ns
	T _{OLVTTL_F16}	16 mA	−0.10	−0.05	−0.05	−0.05	ns
	T _{OLVTTL_F24}	24 mA	−0.10	−0.20	−0.21	−0.23	ns
	T _{OLVCMOS2}	LVC MOS2	0.10	0.10	0.11	0.12	ns
	T _{OPCI33_3}	PCI, 33 MHz, 3.3 V	0.50	2.3	2.5	2.7	ns
	T _{OPCI33_5}	PCI, 33 MHz, 5.0 V	0.40	2.8	3.0	3.3	ns
	T _{OPCI66_3}	PCI, 66 MHz, 3.3 V	0.10	−0.40	−0.42	−0.46	ns
	T _{OGTL}	GTL	0.6	0.50	0.54	0.6	ns
	T _{OGTLP}	GTL+	0.7	0.8	0.9	1.0	ns
	T _{OHSTL_I}	HSTL I	0.10	−0.50	−0.53	−0.5	ns
	T _{OHSTL_III}	HSTL III	−0.10	−0.9	−0.9	−1.0	ns
	T _{OHSTL_IV}	HSTL IV	−0.20	−1.0	−1.0	−1.1	ns
	T _{OSSTL2_I}	SSTL2 I	−0.10	−0.50	−0.53	−0.5	ns
	T _{OSSTL2_II}	SSTL2 II	−0.20	−0.9	−0.9	−1.0	ns
	T _{OSSTL3_I}	SSTL3 I	−0.20	−0.50	−0.53	−0.5	ns
	T _{OSSTL3_II}	SSTL3 II	−0.30	−1.0	−1.0	−1.1	ns
	T _{OCTT}	CTT	0	−0.6	−0.6	−0.6	ns
	T _{OAGP}	AGP	0	−0.9	−0.9	−1.0	ns

Notes:

- Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTTL. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).

Calculation of $T_{i\text{oop}}$ as a Function of Capacitance

$T_{i\text{oop}}$ is the propagation delay from the O Input of the IOB to the pad. The values for $T_{i\text{oop}}$ were based on the standard capacitive load (C_{sl}) for each I/O standard as listed in Table 2.

Table 2: Constants for Calculating $T_{i\text{oop}}$

Standard	Csl (pF)	fl (ns/pF)
LVTTL Fast Slew Rate, 2mA drive	35	0.41
LVTTL Fast Slew Rate, 4mA drive	35	0.20
LVTTL Fast Slew Rate, 6mA drive	35	0.13
LVTTL Fast Slew Rate, 8mA drive	35	0.079
LVTTL Fast Slew Rate, 12mA drive	35	0.044
LVTTL Fast Slew Rate, 16mA drive	35	0.043
LVTTL Fast Slew Rate, 24mA drive	35	0.033
LVTTL Slow Slew Rate, 2mA drive	35	0.41
LVTTL Slow Slew Rate, 4mA drive	35	0.20
LVTTL Slow Slew Rate, 6mA drive	35	0.100
LVTTL Slow Slew Rate, 8mA drive	35	0.086
LVTTL Slow Slew Rate, 12mA drive	35	0.058
LVTTL Slow Slew Rate, 16mA drive	35	0.050
LVTTL Slow Slew Rate, 24mA drive	35	0.048
LVCMS2	35	0.041
PCI 33MHz 5V	50	0.050
PCI 33MHZ 3.3 V	10	0.050
PCI 66 MHz 3.3 V	10	0.033
GTL	0	0.014
GTL+	0	0.017
HSTL Class I	20	0.022
HSTL Class III	20	0.016
HSTL Class IV	20	0.014
SSTL2 Class I	30	0.028
SSTL2 Class II	30	0.016
SSTL3 Class I	30	0.029
SSTL3 Class II	30	0.016
CTT	20	0.035
AGP	10	0.037

Notes:

1. I/O parameter measurements are made with the capacitance values shown above. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
2. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

For other capacitive loads, use the formulas below to calculate the corresponding $T_{i\text{oop}}$.

$$T_{i\text{oop}} = T_{i\text{oop}} + T_{\text{opadjust}} + (C_{\text{load}} - C_{sl}) * fl$$

Where:

T_{opadjust} is reported above in the Output Delay Adjustment section.

C_{load} is the capacitive load for the design.

Table 3: Delay Measurement Methodology

Standard	V_L (1)	V_H (1)	Meas. Point	V_{REF} Typ (2)
LVTTL	0	3	1.4	-
LVCMS2	0	2.5	1.125	-
PCI33_5	Per PCI Spec			-
PCI33_3	Per PCI Spec			-
PCI66_3	Per PCI Spec			-
GTL	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	0.80
GTL+	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	1.0
HSTL Class I	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.75
HSTL Class III	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL Class IV	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
SSTL3 I & II	$V_{REF} - 1.0$	$V_{REF} + 1.0$	V_{REF}	1.5
SSTL2 I & II	$V_{REF} - 0.75$	$V_{REF} + 0.75$	V_{REF}	1.25
CTT	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	1.5
AGP	$V_{REF} - (0.2 \times V_{CCO})$	$V_{REF} + (0.2 \times V_{CCO})$	V_{REF}	Per AGP Spec

Notes:

1. Input waveform switches between V_L and V_H .
2. Measurements are made at V_{REF} (Typ), Maximum, and Minimum. Worst-case values are reported.
3. I/O parameter measurements are made with the capacitance values shown in Table 2. See Application Note XAPP133 on www.xilinx.com for appropriate terminations.
4. I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

Clock Distribution Guidelines

Description	Device	Symbol	Speed Grade			Units
			-6	-5	-4	
Global Clock Skew ⁽¹⁾						
Global Clock Skew between IOB Flip-flops	XCV50	T _{GSKEWIOB}	0.10	0.12	0.14	ns, max
	XCV100		0.12	0.13	0.15	ns, max
	XCV150		0.12	0.13	0.15	ns, max
	XCV200		0.13	0.14	0.16	ns, max
	XCV300		0.14	0.16	0.18	ns, max
	XCV400		0.13	0.13	0.14	ns, max
	XCV600		0.14	0.15	0.17	ns, max
	XCV800		0.16	0.17	0.20	ns, max
	XCV1000		0.20	0.23	0.25	ns, max

Notes:

- These clock-skew delays are provided for guidance only. They reflect the delays encountered in a typical design under worst-case conditions. Precise values for a particular design are provided by the timing analyzer.

Clock Distribution Switching Characteristics

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
GCLK IOB and Buffer						
Global Clock PAD to output.	T _{GPIO}	0.33	0.7	0.8	0.9	ns, max
Global Clock Buffer I input to O output	T _{GIO}	0.34	0.7	0.8	0.9	ns, max

I/O Standard Global Clock Input Adjustments

Description	Symbol	Standard ⁽¹⁾	Speed Grade				Units
			Min	-6	-5	-4	
Data Input Delay Adjustments							
Standard-specific global clock input delay adjustments	T _{GPLVTTL}	LVTTL	0	0	0	0	ns, max
	T _{GPLVCMOS2}	LVC MOS2	−0.02	−0.04	−0.04	−0.05	ns, max
	T _{GP PCI33_3}	PCI, 33 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns, max
	T _{GP PCI33_5}	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns, max
	T _{GP PCI66_3}	PCI, 66 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns, max
	T _{GPGTL}	GTL	0.7	0.8	0.9	0.9	ns, max
	T _{GPGTLP}	GTL+	0.7	0.8	0.8	0.8	ns, max
	T _{GPHSTL}	HSTL	0.7	0.7	0.7	0.7	ns, max
	T _{GPSSTL2}	SSTL2	0.6	0.52	0.51	0.50	ns, max
	T _{GPSSTL3}	SSTL3	0.6	0.6	0.55	0.54	ns, max
	T _{GPCTT}	CTT	0.7	0.7	0.7	0.7	ns, max
	T _{GPAGP}	AGP	0.6	0.54	0.53	0.52	ns, max

Notes:

1. Input timing for GPLVTTL is measured at 1.4 V. For other I/O standards, see [Table 3](#).

CLB Switching Characteristics

Delays originating at F/G inputs vary slightly according to the input used. The values listed below are worst-case. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
4-input function: F/G inputs to X/Y outputs	T _{ILO}	0.29	0.6	0.7	0.8	ns, max
5-input function: F/G inputs to F5 output	T _{IF5}	0.32	0.7	0.8	0.9	ns, max
5-input function: F/G inputs to X output	T _{IF5X}	0.36	0.8	0.8	1.0	ns, max
6-input function: F/G inputs to Y output via F6 MUX	T _{IF6Y}	0.44	0.9	1.0	1.2	ns, max
6-input function: F5IN input to Y output	T _{F5INY}	0.17	0.32	0.36	0.42	ns, max
Incremental delay routing through transparent latch to XQ/YQ outputs	T _{IFNCTL}	0.31	0.7	0.7	0.8	ns, max
BY input to YB output	T _{BYYB}	0.27	0.53	0.6	0.7	ns, max
Sequential Delays						
FF Clock CLK to XQ/YQ outputs	T _{CKO}	0.54	1.1	1.2	1.4	ns, max
Latch Clock CLK to XQ/YQ outputs	T _{CKLO}	0.6	1.2	1.4	1.6	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾	Setup Time / Hold Time					
4-input function: F/G Inputs	T _{ICK} /T _{CKI}	0.6 / 0	1.2 / 0	1.4 / 0	1.5 / 0	ns, min
5-input function: F/G inputs	T _{IF5CK} /T _{CKIF5}	0.7 / 0	1.3 / 0	1.5 / 0	1.7 / 0	ns, min
6-input function: F5IN input	T _{F5INCK} /T _{CKF5IN}	0.46 / 0	1.0 / 0	1.1 / 0	1.2 / 0	ns, min
6-input function: F/G inputs via F6 MUX	T _{IF6CK} /T _{CKIF6}	0.8 / 0	1.5 / 0	1.7 / 0	1.9 / 0	ns, min
BX/BY inputs	T _{DICK} /T _{CKDI}	0.30 / 0	0.6 / 0	0.7 / 0	0.8 / 0	ns, min
CE input	T _{CECK} /T _{CKCE}	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR/BY inputs (synchronous)	T _{RCK} T _{CKR}	0.33 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{CH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{CL}	0.8	1.5	1.7	2.0	ns, min
Set/Reset						
Minimum Pulse Width, SR/BY inputs	T _{RPW}	1.3	2.5	2.8	3.3	ns, min
Delay from SR/BY inputs to XQ/YQ outputs (asynchronous)	T _{RQ}	0.54	1.1	1.3	1.4	ns, max
Delay from GSR to XQ/YQ outputs	T _{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max
Toggle Frequency (MHz) (for export control)	F _{TOG} (MHz)	625	333	294	250	MHz

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Virtex Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>with</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Output Delay Adjustments.	T _{ICKOFDLL}	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).
3. DLL output jitter is already included in the timing calculation.

Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>without</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Input and Output Delay Adjustments. For I/O standards requiring V _{REF} such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T _{ICKOF}	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).

Date	Version	Revision
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed..." statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul style="list-style-type: none"> Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	<ul style="list-style-type: none"> Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/02/01	2.5	<ul style="list-style-type: none"> Revised minimums for Global Clock Set-Up and Hold for LVTTTL Standard, with DLL. Converted file to modularized format. See the Virtex Data Sheet section.
04/19/01	2.6	<ul style="list-style-type: none"> Clarified TIOCKP and TIOCKON IOB Output Switching Characteristics descriptors.
07/19/01	2.7	<ul style="list-style-type: none"> Under Absolute Maximum Ratings, changed (T_{SOL}) to 220 °C.
07/26/01	2.8	<ul style="list-style-type: none"> Removed T_{SOL} parameter and added footnote to Absolute Maximum Ratings table.
10/29/01	2.9	<ul style="list-style-type: none"> Updated the speed grade designations used in data sheets, and added Table 1, which shows the current speed grade designation for each device.
02/01/02	3.0	<ul style="list-style-type: none"> Added footnote to DC Input and Output Levels table.
07/19/02	3.1	<ul style="list-style-type: none"> Removed mention of MIL-M-38510/605 specification. Added link to xapp158 from the Power-On Power Supply Requirements section.
09/10/02	3.2	<ul style="list-style-type: none"> Added Clock CLK to IOB Input Switching Characteristics and IOB Output Switching Characteristics.
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs:
Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs:
Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs:
DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs:
Pinout Tables (Module 4)

Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V _{CCO} , Bank 7	All	G4, H4	G23, K26, N23	A31, L28, L31	C32, D33, K33, N32, T33
V _{REF} Bank 0 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all VREF pins are general I/O.	XCV50	A8, B4	N/A	N/A	N/A
	XCV100/150	... + A4	A16, C19, C21	N/A	N/A
	XCV200/300	... + A2	... + D21	B19, D22, D24, D26	N/A
	XCV400	N/A	N/A	... + C18	A19, D20, D26, E23, E27
	XCV600	N/A	N/A	... + C24	... + E24
	XCV800	N/A	N/A	... + B21	... + E21
	XCV1000	N/A	N/A	N/A	... + D29
V _{REF} Bank 1 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all VREF pins are general I/O.	XCV50	A17, B12	N/A	N/A	N/A
	XCV100/150	... + B15	B6, C9, C12	N/A	N/A
	XCV200/300	... + B17	... + D6	A13, B7, C6, C10	N/A
	XCV400	N/A	N/A	... + B15	A6, D7, D11, D16, E15
	XCV600	N/A	N/A	... + D10	... + D10
	XCV800	N/A	N/A	... + B12	... + D13
	XCV1000	N/A	N/A	N/A	... + E7
V _{REF} Bank 2 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all VREF pins are general I/O.	XCV50	C20, J18	N/A	N/A	N/A
	XCV100/150	... + F19	E2, H2, M4	N/A	N/A
	XCV200/300	... + G18	... + D2	E2, G3, J2, N1	N/A
	XCV400	N/A	N/A	... + R3	G5, H4, L5, P4, R1
	XCV600	N/A	N/A	... + H1	... + K5
	XCV800	N/A	N/A	... + M3	... + N5
	XCV1000	N/A	N/A	N/A	... + B3

Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V_{REF} Bank 3 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	M18, V20	N/A	N/A	N/A
	XCV100/150	... + R19	R4, V4, Y3	N/A	N/A
	XCV200/300	... + P18	... + AC2	V2, AB4, AD4, AF3	N/A
	XCV400	N/A	N/A	... + U2	V4, W5, AD3, AE5, AK2
	XCV600	N/A	N/A	... + AC3	... + AF1
	XCV800	N/A	N/A	... + Y3	... + AA4
	XCV1000	N/A	N/A	N/A	... + AH4
V_{REF} Bank 4 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	V12, Y18	N/A	N/A	N/A
	XCV100/150	... + W15	AC12, AE5, AE8,	N/A	N/A
	XCV200/300	... + V14	... + AE4	AJ7, AL4, AL8, AL13	N/A
	XCV400	N/A	N/A	... + AK15	AL7, AL10, AL16, AM4, AM14
	XCV600	N/A	N/A	... + AK8	... + AL9
	XCV800	N/A	N/A	... + AJ12	... + AK13
	XCV1000	N/A	N/A	N/A	... + AN3
V_{REF} Bank 5 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	V9, Y3	N/A	N/A	N/A
	XCV100/150	... + W6	AC15, AC18, AD20	N/A	N/A
	XCV200/300	... + V7	... + AE23	AJ18, AJ25, AK23, AK27	N/A
	XCV400	N/A	N/A	... + AJ17	AJ18, AJ25, AL20, AL24, AL29
	XCV600	N/A	N/A	... + AL24	... + AM26
	XCV800	N/A	N/A	... + AH19	... + AN23
	XCV1000	N/A	N/A	N/A	... + AK28
V_{REF} Bank 6 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	M2, R3	N/A	N/A	N/A
	XCV100/150	... + T1	R24, Y26, AA25,	N/A	N/A
	XCV200/300	... + T3	... + AD26	V28, AB28, AE30, AF28	N/A
	XCV400	N/A	N/A	... + U28	V29, Y32, AD31, AE29, AK32
	XCV600	N/A	N/A	... + AC28	... + AE31
	XCV800	N/A	N/A	... + Y30	... + AA30
	XCV1000	N/A	N/A	N/A	... + AH30

Pinout Diagrams

The following diagrams, **CS144 Pin Function Diagram**, page 17 through **FG680 Pin Function Diagram**, page 27, illustrate the locations of special-purpose pins on Virtex FPGAs. Table 5 lists the symbols used in these diagrams. The diagrams also show I/O-bank boundaries.

Table 5: Pinout Diagram Symbols

Symbol	Pin Function
*	General I/O
*	Device-dependent general I/O, n/c on smaller devices
V	V _{CCINT}
v	Device-dependent V _{CCINT} , n/c on smaller devices
O	V _{CCO}
R	V _{REF}
r	Device-dependent V _{REF} , remains I/O on smaller devices
G	Ground
Ø, 1, 2, 3	Global Clocks

Table 5: Pinout Diagram Symbols (Continued)

Symbol	Pin Function
⑩, ①, ②	M0, M1, M2
⑩, ①, ②, ③, ④, ⑤, ⑥, ⑦	D0/DIN, D1, D2, D3, D4, D5, D6, D7
B	DOUT/BUSY
D	DONE
P	PROGRAM
I	INIT
K	CCLK
W	WRITE
S	CS
T	Boundary-scan Test Access Port
+	Temperature diode, anode
–	Temperature diode, cathode
n	No connect

CS144 Pin Function Diagram

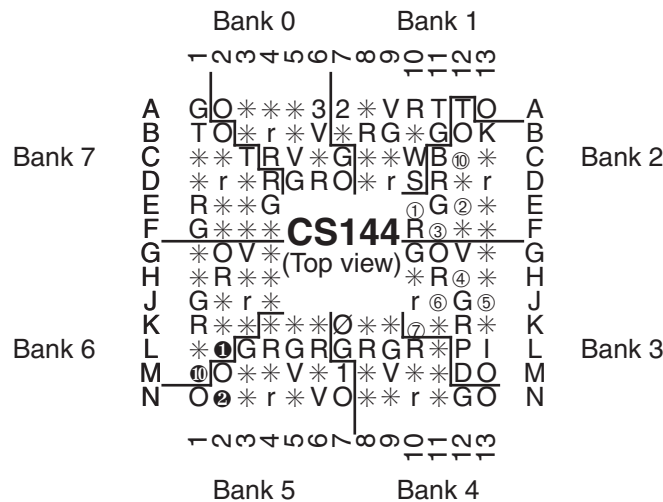
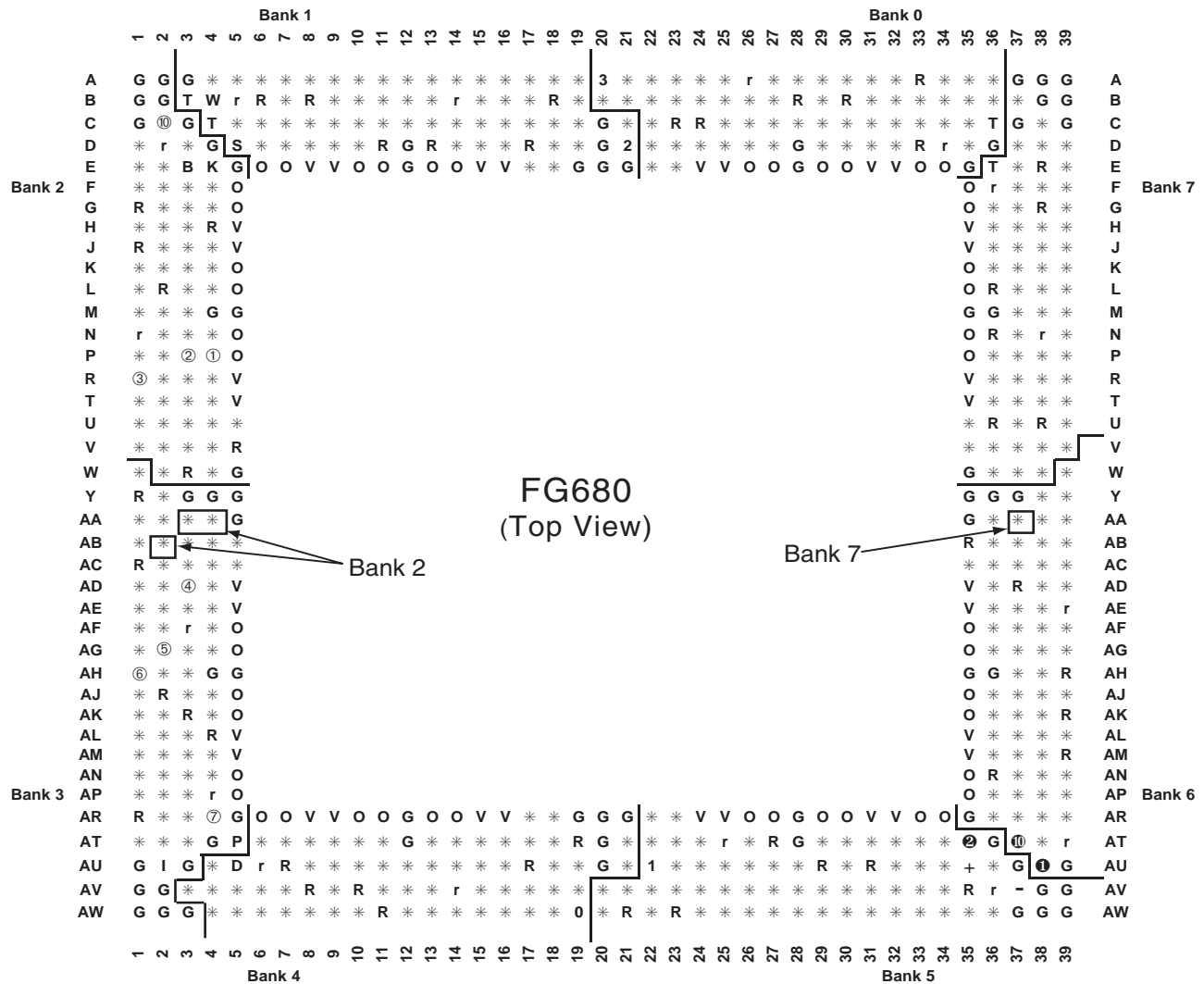


Figure 1: CS144 Pin Function Diagram

FG680 Pin Function Diagram



Note: AA3, AA4, and AB2 are in Bank 2

Note: AA37 is in Bank 7

fg680_12a

Figure 11: FG680 Pin Function Diagram